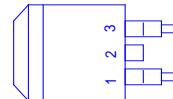
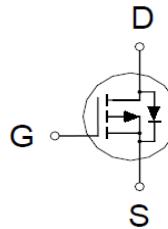


NIKO-SEM**P-Channel Enhancement Mode Field Effect Transistor**
P1604ES
TO-263
Halogen-Free & Lead-Free
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-40V	16mΩ	-65A


1. GATE
2. DRAIN
3. SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS		UNITS
Drain-Source Voltage		V_{DS}	-40		V
Gate-Source Voltage		V_{GS}	±20		V
Continuous Drain Current ²	$T_C = 25^\circ\text{C}$	I_D	-65		A
	$T_C = 100^\circ\text{C}$		-42		
Pulsed Drain Current ^{1,2}		I_{DM}	-120		
Avalanche Current		I_{AS}	-46		
Avalanche Energy	$L = 0.1 \text{ mH}$	E_{AS}	107		mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	104		W
	$T_C = 100^\circ\text{C}$		41		
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150		°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		1.2	°C / W

¹Pulse width limited by maximum junction temperature.²Limited only by maximum temperature allowed.**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-40			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-1.5	-2.2	-3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			±100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -32V, V_{GS} = 0V$			1	μA
		$V_{DS} = -30V, V_{GS} = 0V, T_J = 70^\circ\text{C}$			10	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = -5V, V_{GS} = -10V$	-120			A
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = -7V, I_D = -15A$		14	20	$\text{m}\Omega$
		$V_{GS} = -10V, I_D = -25A$		12	16	
Forward Transconductance ¹	g_{fs}	$V_{DS} = -10V, I_D = -25A$	29			S

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DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = -15V, f = 1MHz$	2229			pF
Output Capacitance	C_{oss}		334			
Reverse Transfer Capacitance	C_{rss}		293			
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	4.3			Ω
Total Gate Charge ²	Q_g	$V_{DS} = 0.5V_{(BR)DSS}, V_{GS} = -10V, I_D = -25A$	48			nC
Gate-Source Charge ²	Q_{gs}		9			
Gate-Drain Charge ²	Q_{gd}		15			
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DS} = 0.5V_{(BR)DSS}, I_D \approx -25A, V_{GS} = -10V, R_{GEN} = 6\Omega$	15			nS
Rise Time ²	t_r		43			
Turn-Off Delay Time ²	$t_{d(off)}$		62			
Fall Time ²	t_f		50			
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS						
Continuous Current	I_S				-65	A
Forward Voltage ¹	V_{SD}	$I_F = -25A, V_{GS} = 0V$			-1.3	V
Reverse Recovery Time	t_{rr}	$I_F = -25A, dI_F/dt = 100A/\mu S$	27			nS
Reverse Recovery Charge	Q_{rr}		16			nC

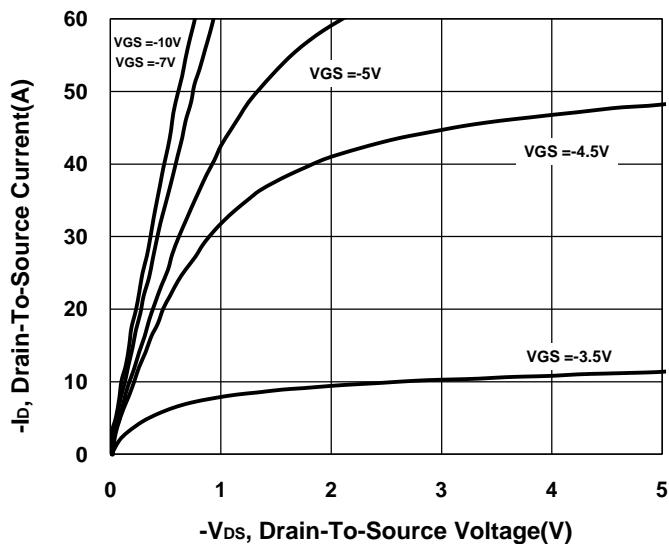
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

NIKO-SEM

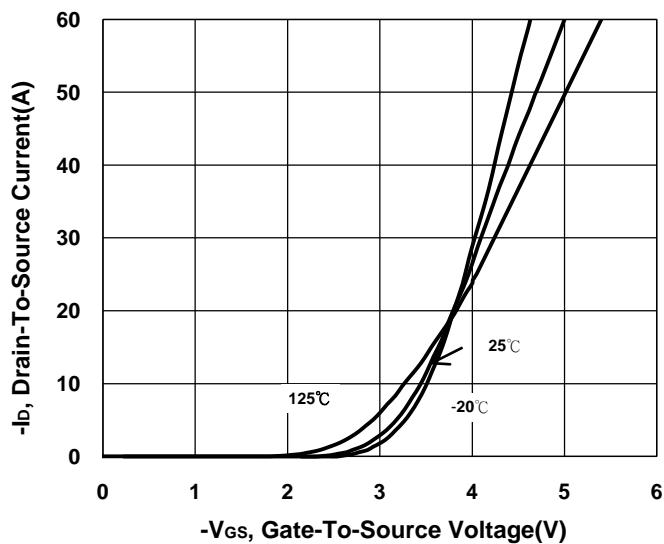
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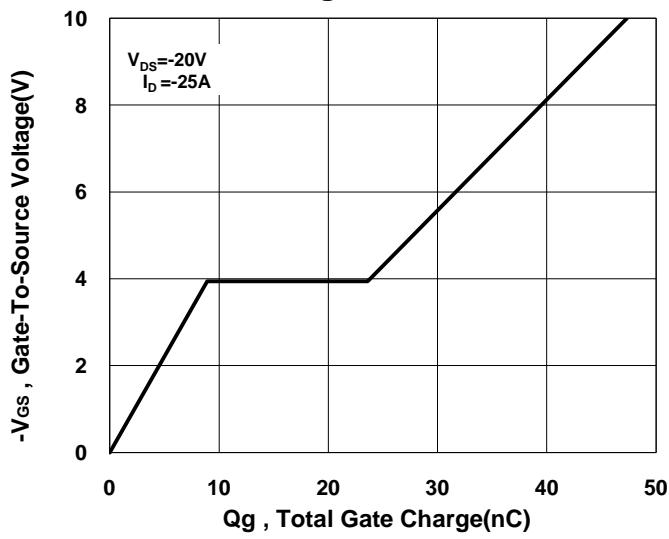
Output Characteristics



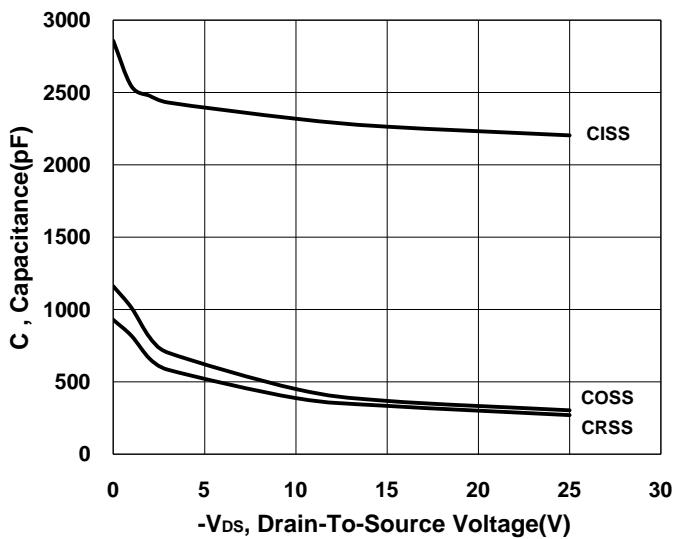
Transfer Characteristics



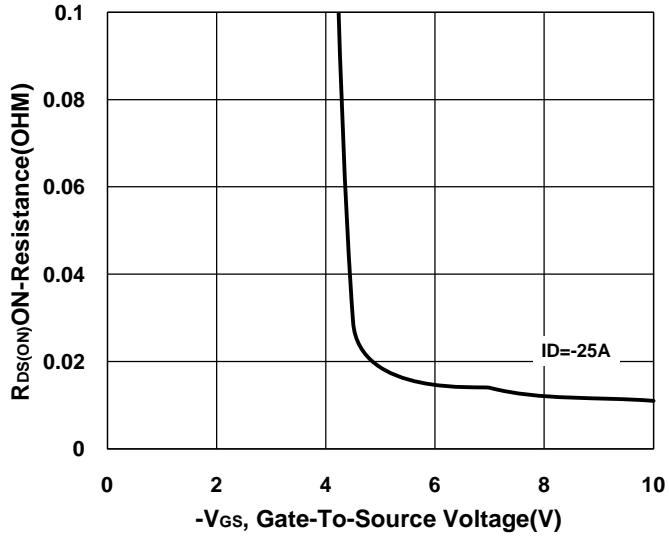
Gate charge Characteristics



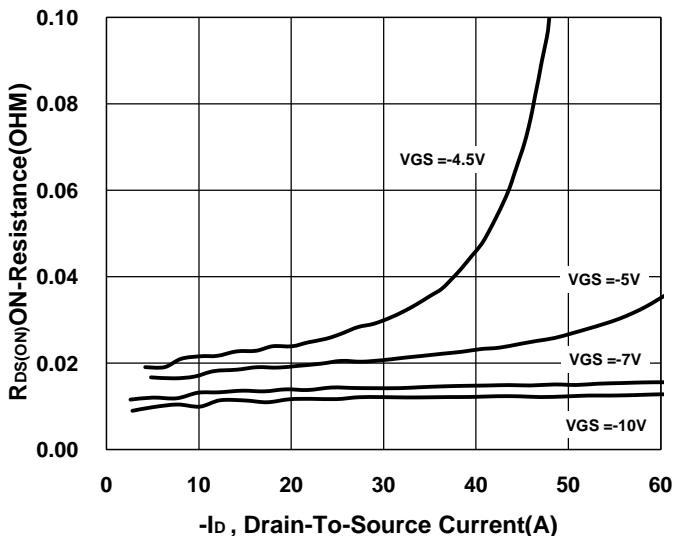
Capacitance Characteristic



On-Resistance VS Temperature

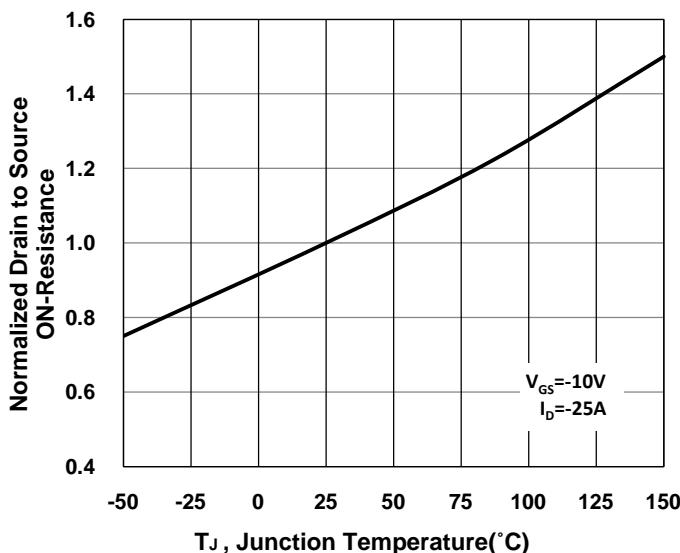
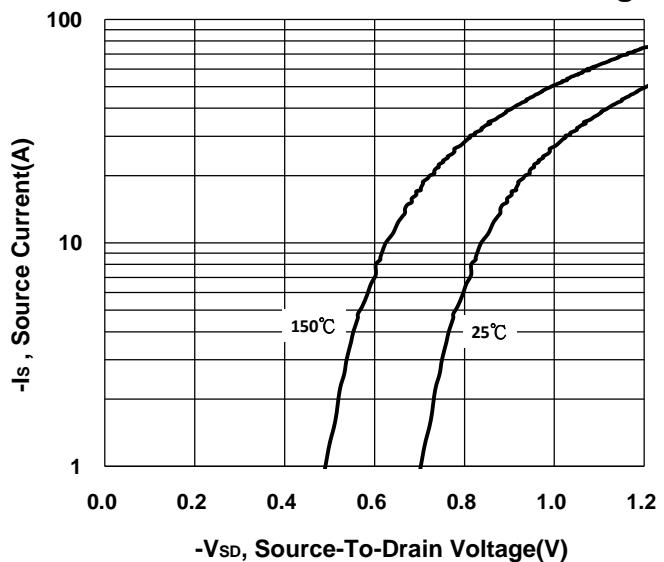
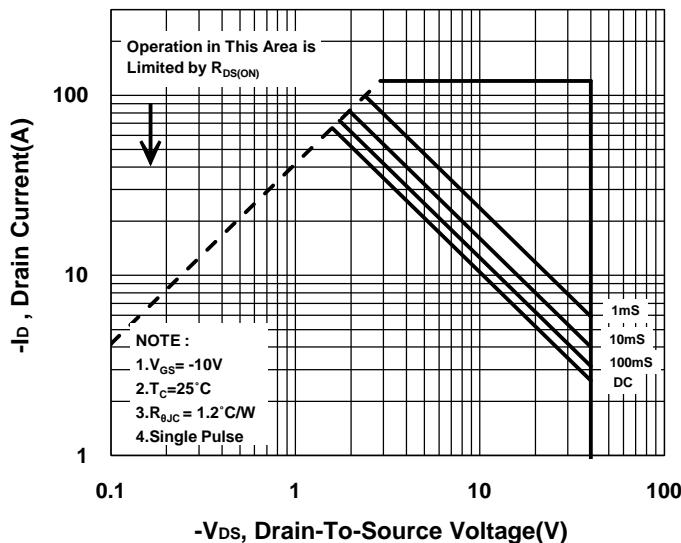
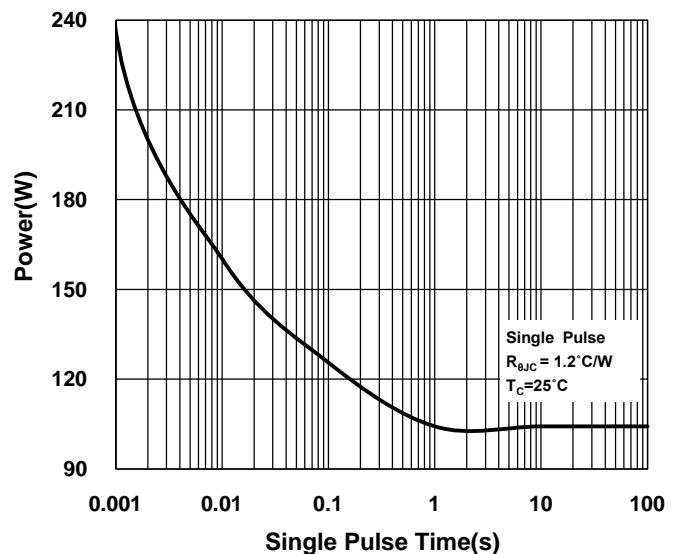


On-Resistance VS Drain Current



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On-Resistance VS Gate-To-Source**Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**